Silicon P Channel MOS Type (U-MOSII)/Silicon Epitaxial Schottky Barrier Diode

# SSM5G04TU

#### DC-DC Converter

Unit: mm

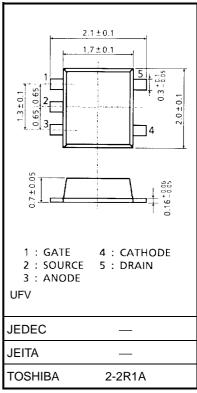
- Combined Pch MOSFET and Schottky Diode into one Package.
- Low RDS (ON) and Low VF

# **Maximum Ratings (Ta = 25°C) MOSFET**

Characteristics		Symbol	Rating	Unit	
Drain-Source voltage		$V_{DS}$	-12	V	
Gate-Source voltag	Gate-Source voltage		±12	V	
Drain current	DC	I <sub>D</sub>	-1.0	Α	
	Pulse	I <sub>DP</sub> (Note 2)	-2.0	A	
Drain power dissipation		P <sub>D</sub> (Note 1)	0.5	W	
		t = 10s	0.8	VV	
Channel temperature		T <sub>ch</sub>	150	°C	

## Maximum Ratings (Ta = 25°C) SCHOTTKY DIODE

Characteristics	Symbol	Rating	Unit
Maximum (peak) reverse voltage	$V_{RM}$	15	V
Reverse voltage	$V_{R}$	12	V
Average forward current	Io	0.5	Α
Peak one cycle surge forward current (non-repetitive)	I <sub>FSM</sub>	2 (50 Hz)	Α
Junction temperature	Tj	125	°C



Weight: 7 mg (typ.)

# Maximum Ratings (Ta = 25°C) MOSFET, DIODE COMMON

Characteristics	Symbol	Rating	Unit
Storage temperature	T <sub>stg</sub>	-55~125	°C
Operating temperature	T <sub>opr</sub> (Note 3)	-40~85	°C

Note 1: Mounted on FR4 board

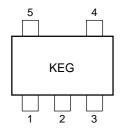
 $(25.4 \text{ mm} \times 25.4 \text{ mm} \times 1.6 \text{ t}, \text{ Cu pad: } 645 \text{ mm}^2)$ 

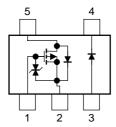
Note 2: The pulse width limited by max channel temperature.

Note 3: Operating temperature limited by max channel temperature and max junction temperature.

## Marking

# **Equivalent Circuit**





# **Handling Precaution**

When handling individual devices (which are not yet mounting on a circuit board), be sure that the environment is protected against electrostatic discharge. Operators should wear anti-static clothing and use containers and other objects that are made of anti-static materials.

The Channel-to-Ambient thermal resistance  $R_{th}$  (ch-a) and the drain power dissipation  $P_D$  vary according to the board material, board area, board thickness and pad area. When using this device, please take heat dissipation fully into account.

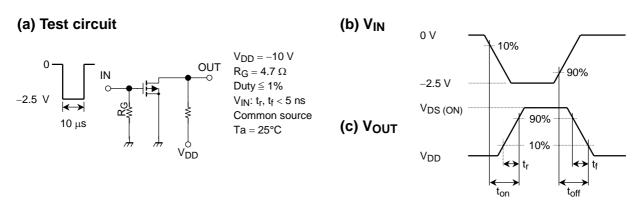
#### **MOSFET**

## **Electrical Characteristics (Ta = 25°C)**

Characteristic		Symbol	Test Condition	Min	Тур.	Max	Unit	
Gate leakage current		I <sub>GSS</sub>	$V_{GS} = \pm 10 \text{ V}, V_{DS} = 0$	_	_	±1	μΑ	
Drain-Source breakdown voltage		V (BR) DSS	$I_D = -1 \text{ mA}, V_{GS} = 0$	-12	_	_	V	
		V (BR) DSX	$I_D = -1 \text{ mA}, V_{GS} = +8 \text{ V}$	-4	_	_	v	
Drain Cut-off current		I <sub>DSS</sub>	$V_{DS} = -12 \text{ V}, V_{GS} = 0$	_	_	-1	μА	
Gate threshold voltage		$V_{th}$	$V_{DS} = -3V$ , $I_D = -0.1$ mA	-0.4	_	-1.1	V	
Forward transfer admittance		Y <sub>fs</sub>	$V_{DS} = -3 \text{ V}, I_D = -0.5 \text{ A}$ (Note 4)	0.85	1.75	_	S	
Drain-Source ON resistance		R <sub>DS</sub> (ON)	$I_D = -0.5 \text{ A}, V_{GS} = -4 \text{ V}$ (Note 4)	_	200	240	mΩ	
			$I_D = -0.5 \text{ A}, V_{GS} = -2.5 \text{ V}$ (Note 4)	_	320	420		
Input capacitance		C <sub>iss</sub>	$V_{DS} = -10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	_	170	_	pF	
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS} = -10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	_	32	_	pF	
Output capacitance		C <sub>oss</sub>	$V_{DS} = -10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	_	58	_	pF	
Switching time	Turn-on time	t <sub>on</sub>	$V_{DD} = -10 \text{ V}, I_D = -0.5 \text{ A}$	_	18	_	no	
	Turn-off time	t <sub>off</sub>	$V_{GS} = 0 \sim -2.5 \text{ V}, R_G = 4.7 \Omega$	_	14	_	ns	

Note 4: Pulse measurement

## **Switching Time Test Circuit**



## **Precaution**

 $V_{th} \ can \ be \ expressed \ as \ voltage \ between \ gate \ and \ source \ when \ low \ operating \ current \ value \ is \ ID = -100 \ \mu A$  for this product. For normal switching operation,  $V_{GS}$  (on) requires higher voltage than  $V_{th}$  and  $V_{GS}$  (off) requires lower voltage than  $V_{th}$ .

(Relationship can be established as follows:  $V_{GS}$  (off) <  $V_{th}$  <  $V_{GS}$  (on))

Please take this into consideration for using the device.

 $V_{\rm GS}$  recommended voltage of  $-2.5~{
m V}$  or higher to turn on this product.

# **Schottky Diode**

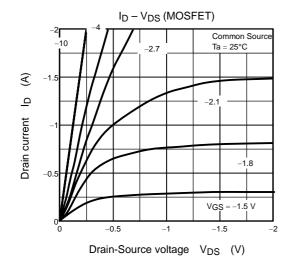
## Electrical Characteristics (Ta = 25°C)

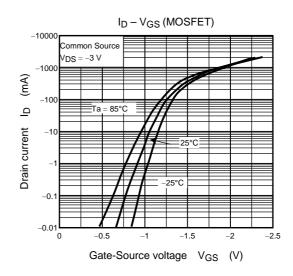
Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Forward voltage	V <sub>F (1)</sub>	I <sub>F</sub> = 0.3 A	_	0.33	0.39	V
	V <sub>F (2)</sub>	I <sub>F</sub> = 0.5 A		0.37	0.43	V
Reverse current	I <sub>R</sub>	V <sub>R</sub> = 12 V	_	_	100	μΑ
Total capacitance	C <sub>T</sub>	V <sub>R</sub> = 0 V, f = 1 MHz	_	80	_	pF

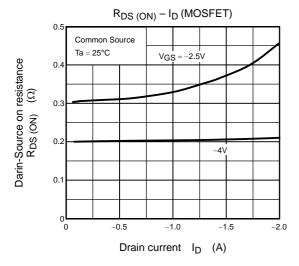
## **Precaution**

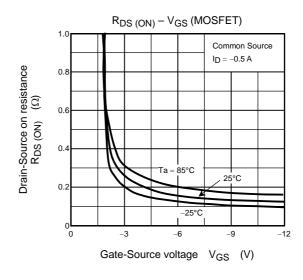
The schottky barrier diode of this product are having large-reverse-current-leakage characteristic compare to the other switching diodes. This current leakage and not proper operating temperature or voltage may cause thermal runaway. Please take forward and reverse loss into consideration when you design.

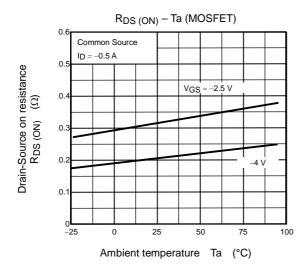
MOSFET Electrical Characteristics Graph

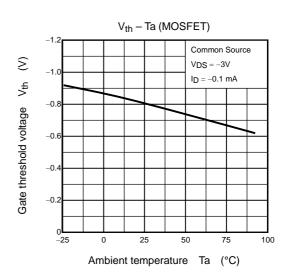


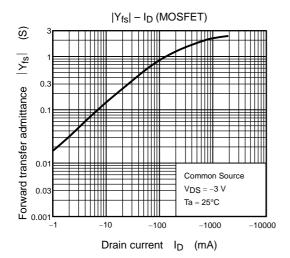


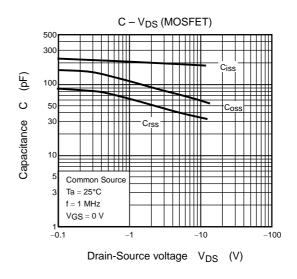


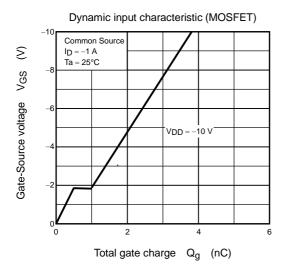


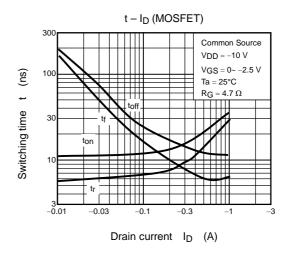


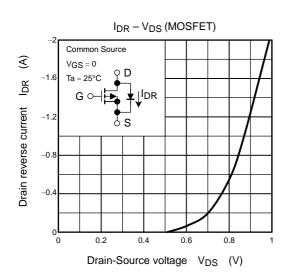




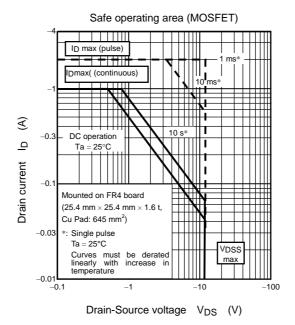


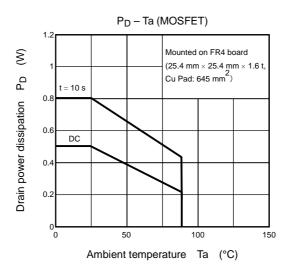




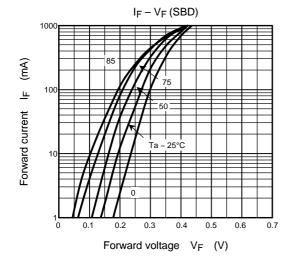


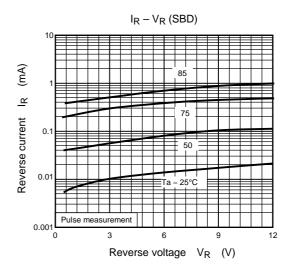
6 2003-04-01

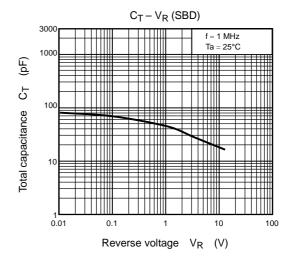




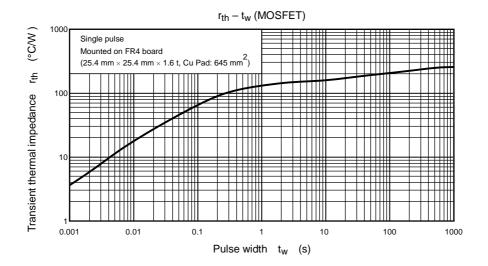
SBD Electrical Characteristics Graoh

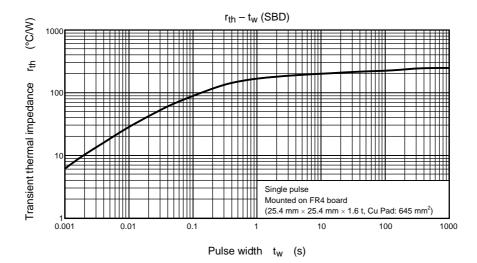






Transient thermal impedance Graph





9 2003-04-01

#### **RESTRICTIONS ON PRODUCT USE**

000707EAA

- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property.
  In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc..
- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.). These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in this document shall be made at the customer's own risk.
- The information contained herein is presented only as a guide for the applications of our products. No
  responsibility is assumed by TOSHIBA CORPORATION for any infringements of intellectual property or other
  rights of the third parties which may result from its use. No license is granted by implication or otherwise under
  any intellectual property or other rights of TOSHIBA CORPORATION or others.

10

• The information contained herein is subject to change without notice.